

Subst. Form PTO-1449 APPLICANT'S(S') INFORMATION DISCLOSURE STATEMENT	Atty. Docket No.: CWR 2 0265	Serial No.: 09/937,227
	Applicant(s): David E. Farrell, et al.	
	Filing Date: March 14, 2002	Group: 2862

U.S. PATENT DOCUMENTS

Initial*		Document No.	Date	Name	Class	Subcl.	Filing Date
Jmf	AA	2,781,488	02/1957	C.W. Zimmerman, et al.	324	13	08/27/1953
	AB	3,299,348	01/1967	J.O. Beauxis, Jr., et al.	324	34	02/08/1963
	AC	3,347,087	10/1967	H. Engelhardt, et al.	73	24	06/01/1964
	AD	3,488,577	01/1970	H. Gross	324	34	09/01/1967
	AE	3,492,566	01/1970	H. Gross	324	34	09/01/1967
	AF	3,534,256	10/1970	C.E. Johnson, Jr.	324	34	09/18/1968
	AG	3,568,050	03/1971	D.L. Dill	324	34	05/29/1969
	AH	3,614,618	10/1971	G.F. Schrader, et al.	324	34 S	05/06/1970
	AI	3,651,397	03/1972	Bodenheimer, et al.	324	34 R	03/09/1970
	AJ	3,665,296	05/1972	Gross, et al.	324	34 S	12/16/1969
	AK	3,665,297	05/1972	Yates	324	34 S	03/04/1970

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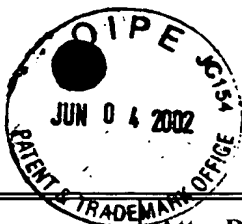
		Document No.	Date	Country	Class	Subcl.	Translation?
	AL						
	AM						
	AN						
	AO						
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OTHER ART

Jmf	AR	D.E. Farrell, J.H. Tripp, P.E. Zanzucchi, J.W. Harris, G.M. Brittenham and W.A. Muir, <u>Magnetic Measurement of Human Iron Stores</u> , IEEE Transactions on Magnetics, Vo. MAG-16, No. 5, pp 818-823, September 1980.
Jmf	AS	Gary M. Brittenham, M.D., David E. Farrell, Ph.D., John W. Harris, M.D., Edward S. Feldman, M.D., Elizabeth H. Danish, M.D., W. Angus Muir, M.D., John H. Tripp, Ph.D. and Errol M. Bellon, M.D., <u>Magnetic-Susceptibility Measurement of Human Iron Stores</u> , New England Journal of Medicine, 307: 1671-1675, December 30, 1982.

Examiner: *Jeanne F. Loh* Date Considered: 10/1/02

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if in conformance and not considered. Include copy of this form with next communication to applicant.



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<i>JD</i>	BA	3,736,500	05/1973	Berkowitz, et al.	324	34 R	10/26/1971
	BB	3,742,344	06/1973	Hummel	324	36	12/29/1971
	BC	3,815,018	06/1974	Gast, et al.	324	36	11/20/1972
	BD	3,826,974	07/1974	Kocache, et al.	324	36	01/15/1973
	BE	3,879,658	04/1975	Hummel	324	36	09/24/1973
	BF	3,934,192	01/1976	de Latour	324	34 R	04/25/1974
	BG	3,980,076	09/1976	Wikswow, Jr., et al.	128	2.05 F	10/02/1974
	BH	4,009,479	02/1977	Cardinne, et al.	357	5	12/21/1973
	BI	4,064,029	12/1977	Wu, et al.	204	192	02/08/1977
	BJ	4,079,730	03/1978	Wikswow, Jr., et al.	128	2.05 F	06/21/1976
<i>JD</i>	BK	4,134,064	01/1979	Jacobs, et al.	324	201	12/27/1976

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	BL						
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<i>JD</i>	BO	X.D. Yu, S.R. Foltyn, P.N. Arendt, W.R. Blumenthal, I.H. Campbell, J.D. Cotton, J.Y. Coulter, W.L. Hults, M.P. Maley, H.F. Safar and J.L. Smith, <u>Properties of YBa₂Cu₃O_{7-x} Thick Films on Flexible Buffered Metallic Substrates</u> , Appl. Phys. Lett., American Institute of Physics, 67 (16), 16 October 1995.
	BP	International Search Report, Form PCT/ISA/210 (second sheet) (July 1998) NOT PROPER DOCUMENT

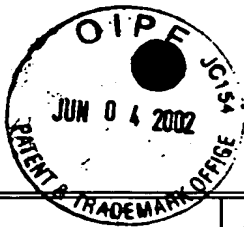
Examiner:

gagnat

Date Considered:

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Initial*		Document No.	Date	Name	Class	Subcl.	Filing Date
<i>JP</i>	CA	4,243,939	01/1981	Grossman, et al.	324	201	08/07/1978
	CB	4,277,750	07/1981	Bonnet, et al.	324	201	02/22/1979
	CC	4,347,622	08/1982	Bernatowicz, et al.	376	245	04/07/1980
	CD	4,507,613	03/1985	Dion	324	340	10/15/1982
	CE	4,588,947	05/1986	Ketchen	324	201	12/30/1983
	CF	4,793,355	12/1988	Crum, et al.	128	653	04/17/1987
	CG	4,827,217	05/1989	Paulson	324	248	04/10/1987
	CH	4,854,163	08/1989	Mount, II, et al.	73	153	09/28/1987
	CI	4,861,990	08/1989	Coley	250	306	02/09/1988
	CJ	4,912,408	03/1990	Sawada, et al.	324	207.13	05/27/1988
<i>↓</i>	CK	4,969,469	11/1990	Mills	128	653 AF	02/14/1989

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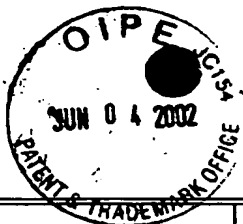
Examiner:

Jaegerfeldt

Date Considered:

10/2/02

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Initial*		Document No.	Date	Name	Class	Subcl.	Filing Date
Jat	DA	5,004,726	04/1991	Shaulov, et al.	505	1	07/14/1989
	DB	5,012,674	05/1991	Millheim, et al.	73	153	10/31/1988
	DC	5,073,858	12/1991	Mills	364	413.13	11/10/1988
	DD	5,166,612	11/1992	Murdock	324	207.13	11/13/1990
	DE	5,252,920	10/1993	Date, et al.	324	228	05/20/1992
	DF	5,280,240	01/1994	Shaulov, et al.	324	239	11/19/1991
	DG	5,283,524	02/1994	Shaulov, et al.	324	239	11/19/1991
	DH	5,311,125	05/1994	Krause, et al.	324	201	03/18/1992
	DI	5,408,178	04/1995	Wikswow, Jr., et al.	324	201	05/17/1991
	DJ	5,444,372	08/1995	Wikswow, Jr., et al.	324	248	07/22/1992
DK	5,491,411	02/1996	Wellstood, et al.	324	248	05/14/1993	

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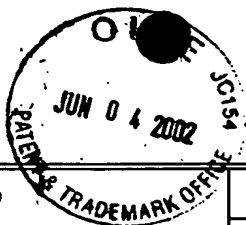
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Examiner: *Joeyntala* Date Considered: 10/1/02

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<i>Jmf</i>	EA	5,506,500	04/1996	Krause, et al.	324	201	04/22/1994
	EB	5,523,686	06/1996	Kirtley, et al.	324	248	08/30/1994
	EC	5,572,123	11/1996	Wiksw, Jr., et al.	324	263	06/07/1995
	ED	5,589,772	12/1996	Kugai	324	240	07/12/1994
	EE	5,610,517	03/1997	Ma, et al.	324	233	06/07/1995
	EF	5,771,894	06/1998	Richards, et al.	128	653.1	04/28/1997
	EG	5,834,938	11/1998	Odawara, et al.	324	248	08/16/1996
	EH	5,963,032	10/1999	Kugai	324	240	08/08/1997
	EI	5,990,678	11/1999	Kugai	324	240	05/24/1996
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Examiner:

Jaymefab

Date Considered: 19/1/02

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